

Notice of References Cited	Application/Control No. 10/641,143	Applicant(s)/Patent Under Reexamination PARK ET AL.	
	Examiner Chen-Wen Jiang	Art Unit 3744	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,309,733 A	05-1994	Hayashida et al.	62/278
	B	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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